Compan		National Semiconductor	またのでは、 またのでは、 またのでは、 していたのでは、 しいたのでは、 しいたの				
National Semic	onductor	The Sight & Sound of Information	http://www.national.com/quality/green/				
Contact	- CP	Title	Phone	Email			
Gloria Gordon	Engineer	ing Project Manager	1-408-721-8435	<u>Green.</u>	project@nsc.	<u>com</u>	
Part Numb	er	MSL Rating	Peak Body Temp C	MaxTime (Sec)	Cycles		
TP3420AV309		3	220	30	4		
Document Date	ontains Lea	d(Pb) and is NOT Europ	pean RoHS Complian	Weight (mg)	Unit Type	A Long	
5-May-2007		NOT China RoHS Co		676.000	Each	COM	
Homo	geneous	Material Composit	ion Declaration f	or Electronic	Products		
ltem	Weight (mg)	Component	CAS#	Weight (mg)	ltem-ppm	Part-ppn	
Plastic	452.200		60676-86-0	339.150	750,000	501,7	
		Epoxy Resin	2592 <mark>8-94-3</mark>	104.910	232,000	155,1	
		Sb2O3	1309-64-4	5.426	12,000	8,0	
and the local sector of th	Card Ltd	Brominated Epoxy	40039-93-8	2.713	6,000	4,0	
Leadframe	189.540	Cu	7440-50-8	184.707	974,500	273,2	
		Fe	7439-89-6	4.549	24,000	6,7	
		Zn	7440-66-6	0.227	1,200	3	
		Р	7723-14-0	0.057	300	144	
Ext. LeadFinish	18.080	Sn	7440-31-5	15.368	850,000	22,7	
		Pb	7439-92-1	2.712	150,000	4,0	
Chip	12.580	Si	7440-21-3	12.505	994,000	18,4	
		AI	7429-90-5	0.075	6,000		
Int. LeadFinish	1.400	Ag	7440-22-4	1.400	1,000,000	2,0	
Die Attach	1.280		7440-22-4	0.960	750,000	1,4	
		Epoxy Resin	25928-94-3	0.320	250,000		
Additionally, the following 1. One or more dopant	s <mark>hould b</mark> e noted: materials may be	Au A	7440-57-5 d on engineering estimates o ub-ppm levels to provide se	0.920 only. It has not been v miconductor propertie	1,000,000 verified through a	1,3	
Note: The device content Additionally, the following 1. One or more dopant	disclosed herewi should be noted: materials may be	Au A	7440-57-5 d on engineering estimates of sub-ppm levels to provide se the specific compound used	0.920 only. It has not been v miconductor propertie , which is considered	1,000,000 verified through a	4 1,3 nalytical test	
Note: The device content Additionally, the following 1. One or more dopant	disclosed herewi should be noted: materials may be	Au A	7440-57-5 d on engineering estimates of sub-ppm levels to provide se the specific compound used	0.920 only. It has not been v miconductor propertie , which is considered	1,000,000 verified through a	1,3	
Note: The device content Additionally, the following 1. One or more dopant 2. Epoxy resin compone RoHS Directive 2002/95/EC	disclosed herewi should be noted: materials may be ents listed are ge RoHS Definiti Chromium, P (100 PPM) of	Au A	7440-57-5 d on engineering estimates of sub-ppm levels to provide se the specific compound used <b>omposition Decla</b> mass (1000 PPM) in homog B), Polybrominated Dipheny admium	0.920 only. It has not been v miconductor propertie , which is considered <b>tration</b> geneous material for: I I Ethers (PBDE) and	1,000,000 verified through an es. I proprietary. Lead (Pb), Mercu quantity limit of C	1, nalytical test ny, Hexavale 0.01% by ma	
Note: The device content Additionally, the following 1. One or more dopant 2. Epoxy resin compone RoHS Directive 2002/95/EC Subject to the limitations b 1. National products wit 2002/95/EC ("RoHS"). T threshold levels, except 2. National products wit not contain other RoHS solder and RoHS exemp 3. National products are Materials and Products are Materials and Products do Deplete the Ozone Laye National has taken comme provided by others or conc default values associated of	disclosed herewi should be noted: materials may be ents listed are ge RoHS Definiti Chromium, P (100 PPM) of below, National S th lead-free solde These products of lead in RoHS ex h lead-containing restricted substa bit applications 5, e manufactured ir and (SC) CSP-9 ity/green/. not contain and er and U.S. Clear ercially reasonabl ducted testing or with internal proc	Au Au th is approximate and is based a present in the silicon die at s neric and may or may not be the <b>ROHS Material Co</b> on: Quantity limit of 0.1% by olybrominated Biphenyls (PBI homogeneous material for Ca emiconductor Corporation ("N r comply with the European U lo not contain homogeneous r empt applications 5, 7a and 7 solder do not comply with Re inces or homogeneous materi 7a and 7c. n conformance with National s -111S2 National's List of Bandar	7440-57-5 d on engineering estimates of sub-ppm levels to provide set the specific compound used <b>DEPOINT</b> mass (1000 PPM) in homog B), Polybrominated Dipheny admium lational") certifies the followin Inion's Directive on the Rest naterials with Joint Industry 'c. oHS, because they contain I als with JIG-101 Level A ma specifications (SC) CSP-9-1 <sup>-11</sup> ned and Reportable Substan- pone depleting substances su ive and accurate information g materials and chemicals. I pe representative of all or acc	0.920 only. It has not been v miconductor propertie , which is considered <b>tration</b> geneous material for: I thers (PBDE) and ng information as of the riction of the Use of H Guide (JIG) -101 Lev ead in a non-exempt aterials above Level A 11C1 Supplier Enviro naces, which are available bject to The Montreal hout may not have in- information provided in tual materials used in	1,000,000 verified through an es. I proprietary. Lead (Pb), Mercu quantity limit of C he document date lazardous Substa vel A materials ab application. The threshold levels, nmental Requirer able at I Protocol on Sub dependently verifi in this document the product (e.g.	1, nalytical test nry, Hexavale 0.01% by ma e. ances ove Level A se products except lead ments for stances that is derived fr the default	

Banned Substance Monitoring						
Part Number	Part Number Document Date					
TP3420AV309	TP3420AV309 5-May-2007					

#### Contains Lead(Pb) and is NOT European RoHS Compliant.

#### NOT China RoHS Compliant

Use	Material	Cd	CrVI	Pb	Hg	PBB	PBDE	Ref #
Device	CHIP	<1	<1	<1	<1	<1	<1	1000
	COMPOUND							
	DIEATTACH							
	EXTLF	<2	<2	149000	<2	NA	NA	56
	FRAME	<100	<1000	<1000	<1000	<1000	<1000	9990
	WIRE	<2	<5	<5	<1	<10	<10	75

\* Cd: Cadmium, CrVI: Hexavalent Chromium, Pb: Lead, Hg: Mercury, ND: Not Detected \* Unless otherwise noted, units are in PPM (parts-per-million)

Ref #	3rd Party Analysis (available upon request, subject to a non-disclosure agreement)
1000	Analysis on 04/17/2007 by Balazs Analytical Services-Freemont CA per Report# 07-01051-07
56	Analysis on 04/27/2007 by SGS per Report# LPCI/07440/07
75	Analysis on 05/16/2007 by ALS per Report# ATJB/3490BS/2007
9990	Analysis pending



## 《电子信息产品污染控制管理办法》的声明

"Electronic Information Products Pollution Control Measures" Statement

#### China RoHS Declaration

产品名称	TP3420AV309
Product Name	11 0 120/ 1000

		有毒有害物 <b>质或元素</b> Toxic and harmful substances or elements						
部件名称 Part	$\overline{}$	<b>铅</b> (Pb)	汞 (Hg)	<b>骤</b> (Cd)	六价 <b>铬</b> (Cr6+)	多 <b>溴联苯</b> (PBB)	多 <b>溴二苯醚</b> (PBDE)	
集成 <b>电路</b> Integrated Circuit		Х	0	0	0	0	0	

### O:表示<mark>该有毒有害物质在该部件所有均质材料中的含量均在SJ/T 11363-2006</mark> 标准规定的限量要求以下。

**O** : Indicates that this hazardous substance contained in all homogeneous materials of this part is below the limit requirement in SJ/T 11363-2006.

#### X:表示该有毒有害物质至少在该部件的某一均质材料中的含量超出 SJ/T 11363-2006 标准规定的限量要求。

**X** : Indicates that this hazardous substance contained in at least one of the homogeneous materials of this part is above the limit requirement in SJ/T 11363-2006.

## 美国国家半**导体的产品不会含有镉、汞、六价铬、多溴联苯(PBB)** 和二苯**醚(PBDE)**。

National Semiconductor's products will not contain cadmium, mercury, hexavalent chromium, polybrominated biphenyls (PBBs) and diphenyl ether (PBDE).



# **环保使用期限(epup)** 是指以符号在这里展出. 环保使用期限(epup) 的有效期只有当产品使用范围以内的数据表中的规格.

The Environmental Protection Use Period (EPUP) is defined by the symbol shown here. The Environmental Protection Use Period (EPUP) is valid only when product is used within the limits of the data sheet specifications.